



## **SCHOTTKY BARRIER RECTIFIER**

REVERSE VOLTAGE - 50 Volts FORWARD CURRENT - 20 Amperes

#### **FEATURES**

- Metal of silicon rectifier, majority carrier conduction
- Guard ring for transient protection
- Low power loss , high efficiency
- High surge & current capability , low VF

#### **APPLICATION**

 For use in Solar Cell junction box as bypass diode for protection, using DC forward current without reverse bias

#### **MECHANICAL DATA**

• Case: TO-263 molded plastic

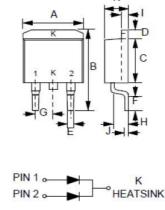
 Case Material: "Green" Molding compound, UL flammability classification 94V- 0, (No Br. Sb. Cl.) "Halogen-free"

Polarity : As marked on bodyWeight : 1.4grams(Approximate)

Mounting position: AnyTerminal finish: Matted plating

• Marking: 20SQ50CG

# D<sup>2</sup>PAK



DIM.	MIN.	MAX.
Α	9.65	10.69
В	14.60	15.88
C	8.25	9.25
D		1.67
E	0.51	1.14
F	2.29	2.79
G	2.29	2.79
Н	2.03	2.92
1	1.14	1.40
J	0.30	0.64
K	4.37	4.83

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### MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Ratings at 25℃ ambient temperature unless otherwis e specified.

#### **ABSOLUTE RATINGS**

PARAMETER		SYMBOL	VALUE	UNIT
Maximum repetitive peak reverse voltage		$V_{RRM}$	50	V
Maximum DC blocking voltage		$V_{DC}$	50	V
Average rectified forward current	@Tc = 120℃	I (AV)	20	Α
Peak forward surge 8.3ms single half sine-way rated load	e superimposed on	I <sub>FSM</sub>	250	Α
Operating and Storage temperature range		$T_{J}, T_{STG}$	-55 ~ +175	G
Junction temperature in DC forward current without reverse bias t≤ 1h (Note 1)		TJ	≦200	C

## STATIC ELECTRICAL CHARACTERISTICS

PARAMETER	TEST	CONDITION	SYMBOL	TYP	MAX	UNIT
Forward voltage	I <sub>F</sub> = 10A	T <sub>J</sub> = 25℃	V <sub>F</sub>	0.51	0.53	V
Reverse leakage current	V <sub>R</sub> = 50V	$T_J = 25$ °C $T_J = 125$ °C	I <sub>R</sub>	25 25	200 80	uA mA
Typical junction capacitance (Note 2)		C₃	750		pF	

#### THERMAL PERFORMANCE

Note:

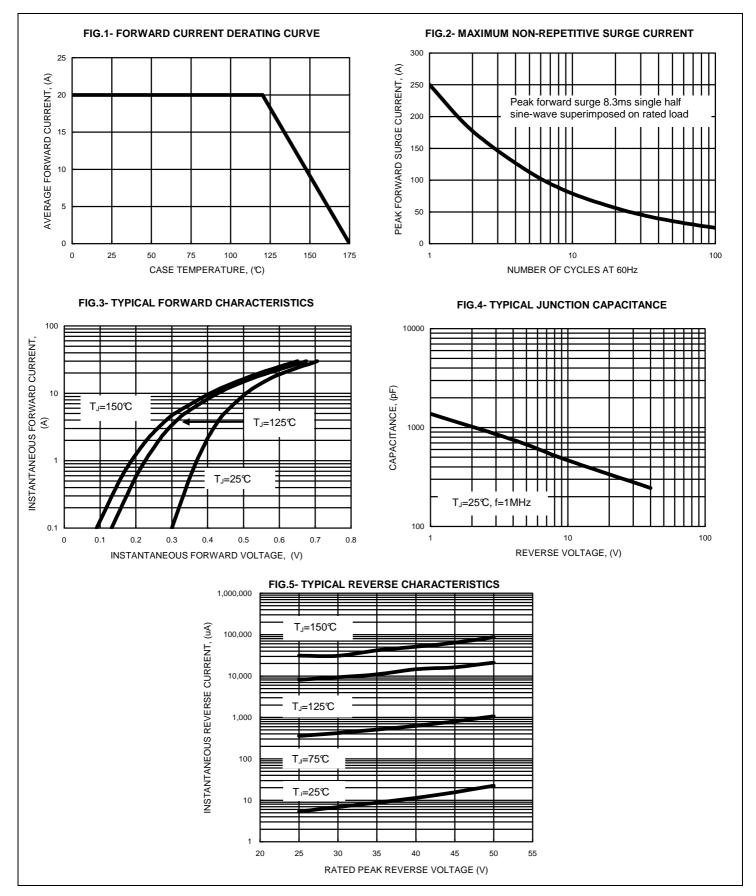
PARAMETER	SYMBOL	ТҮР	UNIT
	$RthJ_A$	20	
Typical thermal resistance (Note 3,4)	$RthJ_L$	1	.c\M
	$RthJ_C$	5	

(1) Meets the requirement of IEC 61215 ed. 2 bypass diode thermal test

- (2) Measured at 1.0MHz and applied reverse voltage of 4.0V<sub>DC</sub>.
- (3) Thermal Resistance Junction to Case and Ambient
- (4) Thermal Resistance test performed in accordance with JESD-51

# RATING AND CHARACTERISTIC CURVES 20SQ50CG







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